

COMPLIANT

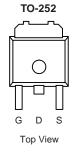
### CED02N9-VB Datasheet

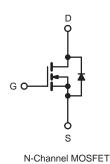
### N-Channel 900 V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	900			
R <sub>DS(on)</sub> (Ω)	$V_{GS} = 10 V$	2.7		
Q <sub>g</sub> (Max.) (nC)	200			
Q <sub>gs</sub> (nC)	24			
Q <sub>gd</sub> (nC)	110			
Configuration	Single			

#### **FEATURES**

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25 °C, unless otherwise noted)

PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	V <sub>DS</sub>	900	v		
Gate-Source Voltage		V <sub>GS</sub>	± 20	v	
Continuous Drain Current	$V_{GS}$ at 10 V $T_C = 25 \degree C$	I <sub>D</sub>	2.0	A	
Continuous Drain Current	$T_{\rm C} = 100 ^{\circ}{\rm C}$		1.5		
Pulsed Drain Current <sup>a</sup>	I <sub>DM</sub>	8.0			
Linear Derating Factor		1.5	W/°C		
Single Pulse Avalanche Energy <sup>b</sup>	E <sub>AS</sub>	470	mJ		
Repetitive Avalanche Current <sup>a</sup>	I <sub>AR</sub>	4.8	A		
Repetitive Avalanche Energy <sup>a</sup>		E <sub>AR</sub>	19	mJ	
Maximum Power Dissipation	T <sub>C</sub> = 25 °C	PD	120	W	
Peak Diode Recovery dV/dt <sup>c</sup>		dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Rang	T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C		
Soldering Recommendations (Peak Temperature)	for 10 s		300 <sup>d</sup>		
Mounting Torque	6-32 or M3 screw		10	lbf ∙ in	
Mounting Torque	0-52 OF WIS SCIEW		1.1	N · m	

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD} = 50 \text{ V}$ , starting  $T_J = 25 \text{ °C}$ , L = 23 mH,  $R_g = 25 \Omega$ ,  $I_{AS} = 7.8 \text{ A}$  (see fig. 12). c.  $I_{SD} \le 7.8 \text{ A}$ , dl/dt  $\le 140 \text{ A/}\mu\text{s}$ ,  $V_{DD} \le 600 \text{ V}$ ,  $T_J \le 150 \text{ °C}$ . d. 1.6 mm from case.

\* Pb containing terminations are not RoHS compliant, exemptions may apply

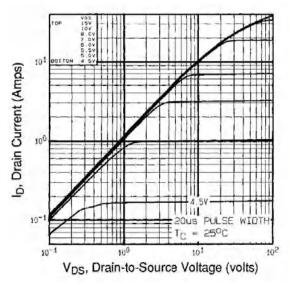
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THERMAL RESISTANCE RATI	NGS							
PARAMETER	SYMBOL	TYP.		MAX.		UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	- 40 0.24 - - 0.65						
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>				°C/W			
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>							
<b>SPECIFICATIONS</b> ( $T_J = 25 \text{ °C}, u$		1						
PARAMETER	SYMBOL	TEST CONDITIONS		IONS	MIN.	TYP.	MAX.	UNIT
Static					1	1	1	1
Drain-Source Breakdown Voltage	V <sub>DS</sub>		= 0 V, I <sub>D</sub> =	-	900	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	I <sub>D</sub> = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> =	250 µA	2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>		$V_{GS} = \pm 20$		-	-	± 100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =	= 800 V, Vo	<sub>as</sub> = 0 V	-	-	100	μA
	220	$V_{DS} = 640 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 ^{\circ}\text{C}$		-	-	-	500	μΑ
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	$V_{GS} = 10 V$	ار	<sub>D</sub> = 1.7 A <sup>b</sup>	-	2.7	-	Ω
Forward Transconductance	<b>g</b> fs	V <sub>DS</sub> =	= 100 V, I <sub>D</sub> =	= 1.7 A <sup>b</sup>	5.6	-	-	S
Dynamic								
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 V,$ $V_{DS} = 25 V,$ f = 1.0 MHz, see fig. 5		-	1800	-	pF	
Output Capacitance	C <sub>oss</sub>			-	500	-		
Reverse Transfer Capacitance	C <sub>rss</sub>			-	290	-		
Total Gate Charge	Qg				-	-	200	nC
Gate-Source Charge	Q <sub>gs</sub>	$V_{GS} = 10 V$		A, $V_{DS} = 400 V$ , iq. 6 and 13 <sup>b</sup>	-	-	24	
Gate-Drain Charge	Q <sub>gd</sub>	1	0001	ig. o and ro	-	-	110	
Turn-On Delay Time	t <sub>d(on)</sub>		•		-	19	-	ns
Rise Time	t <sub>r</sub>		= 400 V, I <sub>D</sub>		-	38	-	
Turn-Off Delay Time	t <sub>d(off)</sub>	R <sub>g</sub> =	= 6.2 Ω, R <sub>D</sub> see fig. 10	= 52 Ω	-	120	-	
Fall Time	t <sub>f</sub>		see lig. It	<u>-</u>	-	39	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-		
Internal Source Inductance	L <sub>S</sub>			-	13	-	nH	
Drain-Source Body Diode Characteristic	S							
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0	•	
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	21	A	
Body Diode Voltage	V <sub>SD</sub>	$T_J$ = 25 °C, $I_S$ = 1.8 A, $V_{GS}$ = 0 V <sup>b</sup>		-	-	1.8	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>	Т. =	25 °C, I <sub>F</sub> =	= 1.8 A.	-	650	980	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	$dl/dt = 100 \text{ A}/\mu\text{s}^{b}$		-	3.8	5.7	μC	
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> and L <sub>D</sub> )						

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.





#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



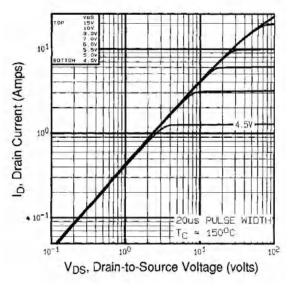


Fig. 2 - Typical Output Characteristics,  $T_C = 150$  °C

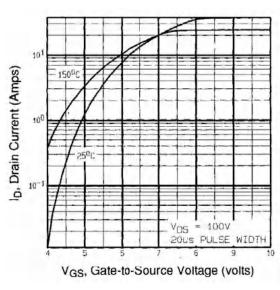


Fig. 3 - Typical Transfer Characteristics

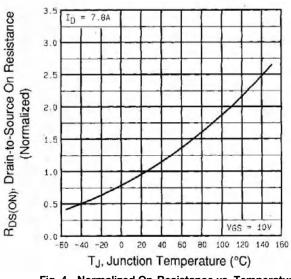


Fig. 4 - Normalized On-Resistance vs. Temperature

### CED02N9-VB



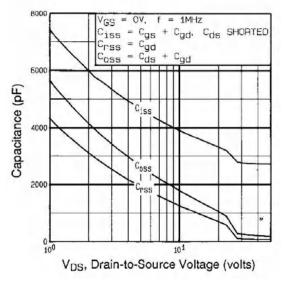


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



Fig. 7 - Typical Source-Drain Diode Forward Voltage

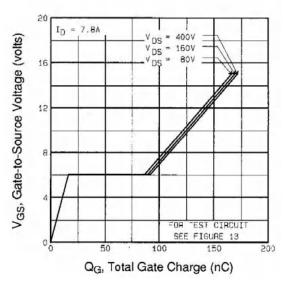
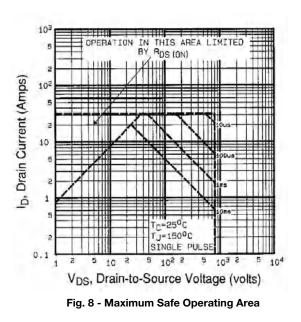


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



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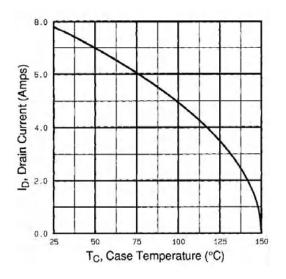


Fig. 9 - Maximum Drain Current vs. Case Temperature

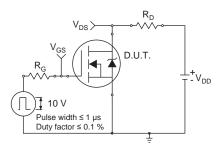


Fig. 10a - Switching Time Test Circuit



Fig. 10b - Switching Time Waveforms

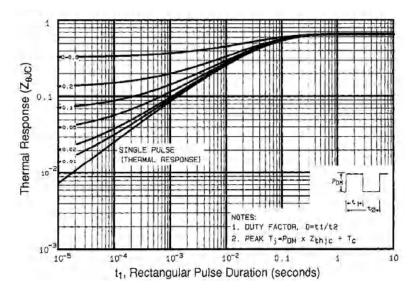


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



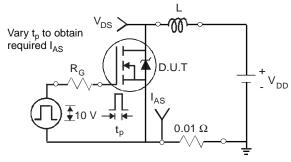


Fig. 12a - Unclamped Inductive Test Circuit

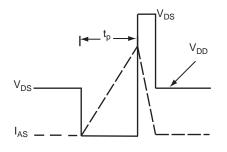


Fig. 12b - Unclamped Inductive Waveforms

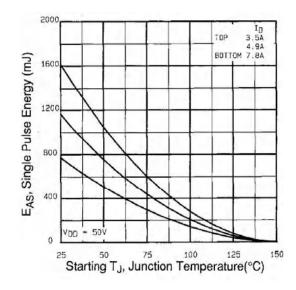


Fig. 12c - Maximum Avalanche Energy vs. Drain Current



Fig. 13a - Basic Gate Charge Waveform

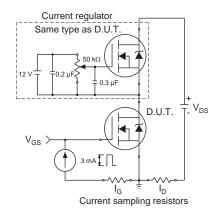
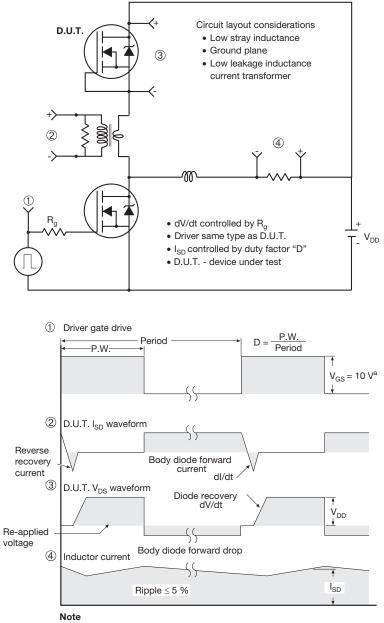


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

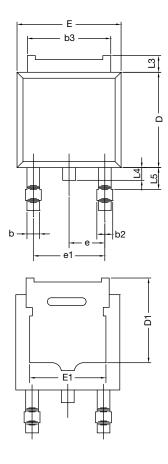


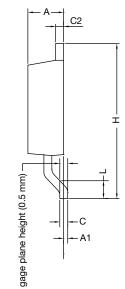
a.  $V_{GS} = 5 V$  for logic level devices

Fig. 14 - For N-Channel



## **TO-252AA CASE OUTLINE**





	MILLIMETERS		INCHES			
DIM.	MIN.	MAX.	MIN.	MAX.		
А	2.18	2.38	0.086	0.094		
A1	-	0.127	-	0.005		
b	0.64	0.88	0.025	0.035		
b2	0.76	1.14	0.030	0.045		
b3	4.95	5.46	0.195	0.215		
С	0.46	0.61	0.018	0.024		
C2	0.46	0.89	0.018	0.035		
D	5.97	6.22	0.235	0.245		
D1	5.21	-	0.205	-		
E	6.35	6.73	0.250	0.265		
E1	4.32	-	0.170	-		
Н	9.40	10.41	0.370	0.410		
е	2.28 BSC		0.090 BSC			
e1	4.56	4.56 BSC		0.180 BSC		
L	1.40	1.78	0.055	0.070		
L3	0.89	1.27	0.035	0.050		
L4	-	1.02	-	0.040		
L5	1.14	1.52	0.045	0.060		
ECN: X12-0247-Rev. M, 24-Dec-12 DWG: 5347						

#### Note

• Dimension L3 is for reference only.



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